Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/767,230	OHNISHI ET AL.	
Examiner	Art Unit	
Andy Huynh	2818	

	SEARCHED					
Class	Subclass	Date	Examiner			
257	E21.277	5/1/2006	АН			
257	758	5/1/2006	АН			
257	759	5/1/2006	АН			
257	760	5/1/2006	АН			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
257	E21.277	5/1/2006	АН		
257	758	5/1/2006	АН		
257	758	5/1/2006	AH		
257/760		5/1/2006	АН		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	5/1/2006	АН		
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Interfernce Search History Printout	5/1/2006	АН		
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